## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | WENDKER ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0102610	05-2005	Jie, Wei	715/513
*	В	US-2003/0084067	05-2003	Obiaya, Chudi	707/104.1
*	C	US-2004/0054546	03-2004	Levin et al.	705/001
*	۵	US-2004/0117383	06-2004	Lee et al.	707/100
	E	US-			
	F	US-			
	G	US-			
	Н	US-			/
	1	US-			
	J	US-	*	·	
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
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	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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